Dear MunEDA Friend & User,

We are pleased to announce the program of our next MUGM MunEDA User Group Meeting 2009. MUGM09 will take place on 2009 November 12&13 (Thu/Fri) at City Hilton in Munich, Germany. Goal of the event is the intensive exchange of experience by industrial users but also an open forum for all technologists interested in MunEDA's DFM-DFY EDA software tools. Besides other contributions one main focus of the MunEDA User Group Meeting 2009 is the special topic:

**Methodologies for Time-Efficient Design, Rapid IP Porting and Technology Migration**

**Selection of Technical & Presentation Topics of MUGM09:**
- Handling Design Contraints & Sizing Rules
- IP Porting & Technology Migration
- Design Performance & Specification Analysis
- Response Surface Modelling & Model Generation
- Circuit Design Optimization & Verification
- Statistical Circuit Analysis & Optimization
- Multi-Testbench Environment & Corner Based Optimization
- Worst-Case Distance Analysis & Optimization
- Design Shrink & Nano-scale Circuit optimization
- Industrial Design Cases
- and much more topics …

**MUGM & MTF Past & Future Forums:**
- Seoul 2010
- Munich 2009
- Yokohama 2009
- Munich 2008
- Boston 2008
- Anaheim 2008
- Taiwan 2007
- Munich 2007
- Munich 2006
- Erfurt 2004
- http://www.muneda.com/MUGM

MunEDA User Group Meeting 2009 Agenda contains high-class and excellent technical contributions from leading semiconductor companies, fabless design houses, foundries, research institutes and universities like STMicroelectronics, Hynix, Infineon, Atmel, Bosch, ZMDI, STARC, Ulm University for Applied Sciences, Technische Universität München, TU Ilmenau, IMMS, Melexis, IPGen, NCU Taiwan and others … (see program agenda on back side)

Registration open at: www.muneda.com/registration

We are very pleased to invite you to our MunEDA User Group Meeting 2009 in Munich.

Andreas Ripp
Vice President Sales & Marketing

AND YOUR TEAM

Dr. Michael Pronath
Vice President Products & Solutions

Participation for MUGM2009 is free but early registration and accommodation is highly recommended as conference seats are limited. For accommodation refer to http://www.muneda.com/MUGM-MTF-MTS_Europe-2009_Accommodation
Day 1 – Thursday, November 12th, 2009

10:00 h - 10:30 h  Registration & Welcome Coffee
10:30 h - 10:45 h  Welcome & What’s new
Andreas Ripp, MunEDA GmbH, Munich, Germany

10:45 h - 11:30 h  KEYNOTE - STARC - Tools, Trends & Strategic Challenges for the Global Semiconductor Industry
Kunihiro Tsuoboi, Semiconductor Technology Academic Research Center, Yokohama, Japan

11:30 h - 12:00 h  STMicroelectronics: WiCkeD - An application of Worst Case Circuit Analysis and Yield Optimization in order to reveal circuit limitations - A Micro-Power Precision Operational Amplifier based on advanced Offset Cancellation Chopper Techniques in HF7CMOS (350 nm) from APM-IMS.
Angelo Ciccazio, STMicroelectronics / MM5-CR&D, Catania, Italy

12:00 h - 13:30 h  Lunch Break

13:30 h - 13:55 h  IPGEN: Automatic Analog IP Generation with: 1Stone
Dirk Friebel, COO, IPGEN, Germany

13:55 h - 14:20 h  STMicroelectronics – WiCkeD Application Case: Design and characterization of a dither VCO for mixed signal application at different level of abstraction
Antonio Colaci, STMicroelectronics, Automotive Products Group, Castelletto - Cornaredo, Italy

14:20 h - 15:05 h  MunEDA: WiCkeD™ 6.0 – Software Tutorial & Release Updates
Bernd Obermeier, MunEDA GmbH, Munich, Germany

15:05 h - 15:30 h  BOSCH - Methods of Usage Measurement for WiCkeD in Bosch Automotive Design Flow
Michael Barth, Robert Bosch GmbH, Reutlingen, Germany

15:30 h - 16:00 h  Coffee & Discussion Break

16:00 h - 16:30 h  LANTIQ: The Stepchild Parametric Yield
Guntram E. Müller-L., Lantiq GmbH, Neubiberg, Germany

16:30 h - 17:00 h  Atmel: Modelling of Multi-Stage Amplifiers with WiCkeD
Wolfgang Schneider, Hans-Werner Groh, Stefan Kern, Atmel Germany GmbH

17:00 h - 17:30 h  Infineon: Architectural Assessment of Design Techniques to Improve Speed and Robustness in Embedded Microprocessor
Thomas Baumann, Infineon Technologies AG, Munich, Germany

17:30 h - 18:00 h  IMMS: Analysis of frequency-optimized transimpedance amplifiers in XFAB 600nm BiCMOS technology
Dominik Krausse, TU Ilmenau/IMMS

From 19:00 h  Social Event

Day 2 – Friday, November 13th, 2009

09:00 h - 09:30 h  MunEDA Tools and R&D-Roadmap
Frank Schenkel, VP Research & Development, MunEDA GmbH, Munich, Germany

09:30 h - 10:00 h  STMicroelectronics: WiCkeD simulation based and modeling approach. A ring oscillator in 65nm non volatile memory technology from TRD-CCDS and a low
Elena Raciti, Central R&D, STMicroelectronics, Atrate, Italy

10:00 h - 10:30 h  TUM Technische Universität München – Towards Reliability Optimization of Analog Integrated Circuits
Helmut Gräb, Technische Universität München, Germany

10:30 h - 11:00 h  Coffee & Discussion Break

11:00 h - 11:25 h  Hynix – Using WiCkeD in DRAM Development
Kwang-Seok Kim, Hynix Semiconductors, Korea

11:25 h - 11:50 h  ZMDI: Analog IP Porting
Enno Böhme, ZMD AG, Dresden, Germany

11:50 h - 12:15 h  NCU National Central University Taiwan - Analog Behavioral Modeling and its Application on Yield Enhancement of Analog Circuits
Chien-Nan (Jimmy) Liu (劉建男), National Central University, Taiwan, R.O.C.

12:15 h - 13:45 h  Lunch Break

13:45 h - 14:15 h  STMicroelectronics: AMS design flow - Trends, strategic tools & innovative methodologies for deep sub-micron technology nodes
Pierluigi Daglio, STMicroelectronics, Atrate, Italy

14:15 h - 14:45 h  IMMS - Design and Optimization of a High-Speed Blu-ray Disc Photodetector IC with WiCkeD
Eckhard Hennig, IMMS GmbH, Erfurt, Germany

14:45 h - 15:15 h  STMicroelectronics: WiCkeD - Statistical Analysis and Optimization of a Sense Amplifier for very low voltage applications in CMOS 90nm Flash technology from IMSS MM5 CR&D
Mario Micciche, Alberto Di Martino, STMicroelectronics, Smart Card Group, Catania, Italy

15:15 h - 15:45 h  Ulm University for Applied Science: Investigations on Performance and Productivity Improvement of CMOS Circuits for Analog Signal Processing with WiCkeD
Florian Mrugalla, Georg Vallant, Gerhard Forster, University for Applied Science Ulm, Germany

15:45 h - 16:15 h  Coffee & Discussion

16:15 h - 16:45 h  Expert Session: WiCkeD - Tool Demos, Q&A & Feedbacks
Bernd Lemaître, Michael Pronath, MunEDA GmbH, Munich, Germany

At 17:45 h  Conference End